

Notice of References Cited	Application/Control No. 10/657,839	Applicant(s)/Patent Under Reexamination BAEK ET AL.	
	Examiner Minh-Loan T. Tran	Art Unit 2826	Page 1 of 1

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	N	WO 02/078409	10-2002	WO	Blom et al.	H05K 1/18
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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